

**INFORMATION DISCLOSURE STATEMENT**

Applicants	: Gonzalez, et al.
App. No.	: Unknown
Filed	: Herewith
For	: DUAL GATE DIELECTRIC CONSTRUCTION
Examiner	: Unknown
Group Art Unit	: Unknown

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Enclosed are copies of forms PTO-1449 and 892 listing 31 references. These references are of record on related application No. 09/879,604, filed June 12, 2001. Therefore, copies of the references are not enclosed. This Information Disclosure Statement is being submitted upon filing, and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1).

Identification herein is not an admission that any of the foregoing references are prior art to the above-captioned application.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: Sept. 12, 2003

By: Michael S. Okamoto

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Attorney of Record  
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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON 0794VIC1	APPLICATION NO. Unknown
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Gonzalez et al.	
		FILING DATE Herewith	GROUP Unknown

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
		4,627,153	12/9/86	Masuoka			
		4,651,406	3/24/87	Shimizu et al.			
		4,957,878	9/18/90	Lowrey et al.			
		4,675,982	6/30/87	Noble, Jr. et al.			
		5,057,449	10/15/91	Lowrey et al.			
		5,264,724	11/23/93	Brown et al.			
		5,358,894	10/25/94	Fazan et al.			
		5,360,769	11/1/94	Thakur et al.			
		5,376,593	12/27/94	Sandhu et al.			
		5,393,683	2/28/95	Mathews et al.			
		5,405,791	4/11/95	Ahmad et al.			
		5,407,870	4/18/95	Okada et al.			
		5,463,234	10/31/95	Toriumi et al.			
		5,502,009	3/26/96	Lin			
		5,668,035	9/16/97	Fang et al.			
		5,863,819	1/26/99	Gonzalez			
		5,966,618	10/12/99	Sun et al.			

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	S. Shimizu, et al., "Impact of Surface Proximity Gettering and Nitrided Oxide Side-Wall Spacer by Nitrogen Implantation on Sub-Quarter Micron CMOS LDD FETs," IEDM 1995, pp. 859-862

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061101

EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.079DV1 C1	APPLICATION NO. <del>09/079,004</del> unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Gonzalez et al.	
		FILING DATE <del>June 12, 2001</del> Herewith	GROUP Unknown

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
		6,033,998	03/07/00	Aronowitz et al.			03/09/98
		6,037,224	03/14/00	Buller et al.			05/02/97
		6,110,842	08/29/00	Okuno et al.			04/22/98

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073101

EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

<b>Notice of References Cited</b>	Application/Control No. 09/879,604 Unknown	Applicant(s)/Patent Under Reexamination GONZALEZ ET AL.	
	Examiner Kevin Quinto	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,101,251	03-1992	Wakamiya et al.	-
X	B	US-5,395,786	03-1995	Hsu et al.	-
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. <b>00/879,604 Unknown</b>		Applicant(s)/Patent Under Reexamination <b>GONZALEZ ET AL</b>	
	Examiner <b>Kevin Quinto</b>		Art Unit <b>2826</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-5,668,035	09-1997	Fang et al.	-
✓	B	US-5,960,289	09-1999	Tsui et al.	-
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
✓	N	JP-08031958-A	02-1996	Japan	Tanaka	-
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. <b>09/879,664 Unknown</b>	Applicant(s)/Patent Under Reexamination <b>GONZALEZ ET AL</b>	
	Examiner <b>Kevin Quinto</b>	Art Unit <b>2826</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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	N					
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	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Sekine et al., "Self-aligned tungsten strapped source/drain and gate technology realizing the lowest sheet resistance for sub-quarter micron CMOS," International Electron Devices Meeting, December 1994, IEEE, p.493-496 ✓
	V	
	W	
	X	

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<b>Notice of References Cited</b>	Application/Control No. <b>09/879,604 Unknown</b>		Applicant(s)/Patent Under Reexamination <b>GONZALEZ ET AL.</b>	
	Examiner <b>Kevin Quinto</b>		Art Unit <b>2826</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,658,811 ✓	08-1997	Kimura et al.	-
	B	US-5,731,238 ✓	03-1998	Cavins et al.	-
	C	US-5,843,817 ✓	12-1998	Lee et al.	-
	D	US-6,136,728 ✓	10-2000	Wang	-
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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	Q					
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	S					
	T					

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